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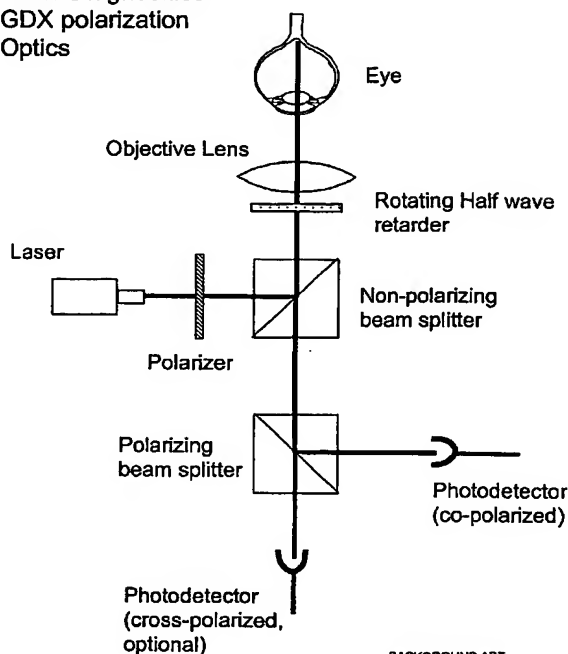
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(54) Title: ADVANCED POLARIZATION IMAGING METHOD, APPARATUS, AND COMPUTER PROGRAM PRODUCT FOR RETINAL IMAGING, LIQUID CRYSTAL TESTING, ACTIVE REMOTE SENSING, AND OTHER APPLICATIONS

Laser Diagnostics
GDx polarization
Optics



(57) Abstract: A method, apparatus, and computer program product for identifying features in a sample by analyzing Mueller matrices to calculate an average degree of polarization, a weighted average degree of polarization, a degree of polarization map, a degree of polarization surface. Also, a method, apparatus, and computer program product for identifying features in a sample by analyzing Mueller matrices to calculate depolarization relative to a retardance axis and/or a diattenuation axis, and to calculate a ratio of diattenuation to polarizance or ratios of row and column magnitudes. Also, a method for retinal polarimetry, including a non-depolarizing light tube configured for insertion into the eye.

BACKGROUND ART

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